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Notice of References Cited	Application/Control No. 09/215,194	Applicant(s)/Patent Under Reexamination IKEGAMI ET AL.	
	Examiner Tanh Q. Nguyen	Art Unit 2182	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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